

ICS 29.050
CCS Q 51

YB

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

YB/T 4590-2017

**Determination of multi-element contents in high purity graphite
used for silicon material. Inductively coupled plasma atomic
emission spectrographic method**

硅材料用高纯石墨制品中杂质含量的测定电感耦合等离子体发射光谱法
(English Translation)

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What this standard covers

This standard specifies the method of inductively coupled plasma emission spectrometry determination of aluminum, calcium, copper, iron, potassium, magnesium, sodium, phosphorus, arsenic, zinc, nickel, chromium and boron in high purity graphite products for polycrystalline silicon. This standard is applicable to the determination of aluminum, calcium, copper, iron, potassium, magnesium, sodium, phosphorus, arsenic, zinc, nickel, chromium and boron in high purity graphite products for polycrystalline silicon.

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